

Abstract

The invention relates to an electromigration test apparatus having a direct-current source 101 and an AC voltage source 102. Furthermore, it has a circuit 104 having a conductive structure 100, which is electrically coupled to the direct-current source 101 and the AC voltage source 102, and a measuring device for measuring an electrical parameter which is indicative of electromigration in the conductive structure. The AC voltage source 102 is set up in such a way that it exposes the conductive structure 100 to an alternating current, independently of a direct current, and thus heats the conductive structure 100 to a predetermined temperature.

(Figure 1)